## Search Notes



Application/Control	No.
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Applicant(s)/Patent Under Reexamination

OKUYAMA ET AL.

Examiner

Art Unit

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ANDREW P BAINBRIDGE

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## SEARCHED

Class	Subclass	Date	Examiner
222	192	3/31/08	APB
250	281-282,286-288,423f,423p,423r,424,435	10/20/2008	APB
378	66,119,210	10/20/2008	APB
361	225-228, 230-235	10/20/2008	APB

## **SEARCH NOTES**

Search Notes	Date	Examiner
Reviewed all IDS	3/31/08	APB
Angstrom and Nanometer	3/28/08	APB
Soft X Ray	3/28/08	APB
Backwards/ forward searched relevant references	10/20/2008	APB

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/A. P. B./ Examiner.Art Unit 3754	

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